

## STM32L422xB device errata

## Applicability

This document applies to the part numbers of STM32L422xB devices and the device variants as stated in this page.

It gives a summary and a description of the device errata, with respect to the device datasheet and reference manual RM394.

Deviation of the real device behavior from the intended device behavior is considered to be a device limitation. Deviation of the description in the reference manual or the datasheet from the intended device behavior is considered to be a documentation erratum. The term “*errata*” applies both to limitations and documentation errata.

**Table 1. Device variants**

Reference	Silicon revision codes	
	Device marking <sup>(1)</sup>	REV_ID <sup>(2)</sup>
STM32L422xB	A	0x1000

1. Refer to the device data sheet for how to identify this code on different types of package.
2. REV\_ID[15:0] bitfield of DBGMCU\_IDCODE register.

# 1 Summary of device errata

The following table gives a quick reference to the STM32L422xB device limitations and their status:

A = workaround available

N = no workaround available

P = partial workaround available

Applicability of a workaround may depend on specific conditions of target application. Adoption of a workaround may cause restrictions to target application. Workaround for a limitation is deemed partial if it only reduces the rate of occurrence and/or consequences of the limitation, or if it is fully effective for only a subset of instances on the device or in only a subset of operating modes, of the function concerned.

**Table 2. Summary of device limitations**

Function	Section	Limitation	Status
			Rev. A
Core	2.1.1	Interrupted loads to SP can cause erroneous behavior	A
	2.1.2	VDIV or VSQRT instructions might not complete correctly when very short ISRs are used	A
	2.1.3	Store immediate overlapping exception return operation might vector to incorrect interrupt	A
System	2.2.1	Internal voltage reference corrupted upon Stop mode entry with temperature sensing enabled	A
	2.2.2	Full JTAG configuration without NJTRST pin cannot be used	A
	2.2.3	Unstable LSI when it clocks RTC or CSS on LSE	P
	2.2.4	LSESYSDIS has no effects if set just before Stop entry	A
	2.2.5	PB8 and PB11 on 48-pin devices with SMPS remain software configurable	A
	2.2.6	First double-word of Flash memory corrupted upon reset or power down while programming	A
FW	2.3.1	Code segment unprotected if non-volatile data segment length is zero	A
QUADSPI	2.4.1	First nibble of data not written after dummy phase	A
	2.4.2	Wrong data from memory-mapped read after an indirect mode operation	A
ADC	2.5.1	Writing ADCx_JSQR when JADCSTART and JQDIS are set might lead to incorrect behavior	N
	2.5.2	Wrong ADC result if conversion done late after calibration or previous conversion	N
	2.5.3	Spurious temperature measurement due to spike noise	A
TSC	2.6.1	Inhibited acquisition in short transfer phase configuration	A
LPTIM	2.8.1	MCU may remain stuck in LPTIM interrupt when entering Stop mode	A
RTC and TAMP	2.9.1	RTC interrupt can be masked by another RTC interrupt	A
	2.9.2	Calendar initialization may fail in case of consecutive INIT mode entry	A
	2.9.3	Spurious RTC alarm EXTI line event following RTC WUT interrupt	A
	2.9.4	RTC_REFIN and RTC_OUT on PB2 not operating in Stop 2 mode	A

Function	Section	Limitation	Status
			Rev. A
I2C	2.10.1	10-bit master mode: new transfer cannot be launched if first part of the address is not acknowledged by the slave	A
	2.10.3	Wrong data sampling when data setup time (t <sub>SU</sub> ;DAT) is shorter than one I2C kernel clock period	P
	2.10.4	Spurious bus error detection in master mode	A
	2.10.5	Last-received byte loss in reload mode	P
	2.10.6	Spurious master transfer upon own slave address match	P
USART	2.11.1	RTS is active while RE = 0 or UE = 0	A
SPI	2.12.1	BSY bit may stay high at the end of data transfer in slave mode	A
	2.12.2	Wrong CRC in full-duplex mode handled by DMA with imbalanced setting of data counters	A
	2.12.3	CRC error in SPI slave mode if internal NSS changes before CRC transfer	P

The following table gives a quick reference to the documentation errata.

**Table 3. Summary of device documentation errata**

Function	Section	Documentation erratum
AES	2.7.1	Burst read or write accesses not supported
	2.7.2	TAG computation in GCM encryption mode
	2.7.3	Section 2.7.3 CCM authentication mode not compliant with NIST CMAC
	2.7.4	Section 2.7.4 Datatype initial configuration in GCM mode
	2.7.5	Section 2.7.5 Wait until BUSY is low when suspending GCM encryption
I2C	2.10.2	Wrong behavior in Stop mode when wakeup from Stop mode is disabled in I2C

## 2 Description of device errata

The following sections describe limitations of the applicable devices with Arm® core and provide workarounds if available. They are grouped by device functions.

**arm**

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### 2.1 Core

Errata notice for the Arm® Cortex®-M4F core revision r0p1 is available from <http://infocenter.arm.com>. Only applicable information from the Arm errata notice is replicated in this document. Extra information may have been added for more clarity.

#### 2.1.1 Interrupted loads to SP can cause erroneous behavior

This limitation is registered under Arm ID number 752770 and classified into “Category B”. Its impact to the device is minor.

##### Description

If an interrupt occurs during the data-phase of a single word load to the stack-pointer (SP/R13), erroneous behavior can occur. In all cases, returning from the interrupt will result in the load instruction being executed an additional time. For all instructions performing an update to the base register, the base register will be erroneously updated on each execution, resulting in the stack-pointer being loaded from an incorrect memory location.

The affected instructions that can result in the load transaction being repeated are:

- LDR SP, [Rn],#imm
- LDR SP, [Rn,#imm]!
- LDR SP, [Rn,#imm]
- LDR SP, [Rn]
- LDR SP, [Rn,Rm]

The affected instructions that can result in the stack-pointer being loaded from an incorrect memory address are:

- LDR SP,[Rn],#imm
- LDR SP,[Rn,#imm]!

As compilers do not generate these particular instructions, the limitation is only likely to occur with hand-written assembly code.

##### Workaround

Both issues may be worked around by replacing the direct load to the stack-pointer, with an intermediate load to a general-purpose register followed by a move to the stack-pointer.

#### 2.1.2 VDIV or VSQRT instructions might not complete correctly when very short ISRs are used

This limitation is registered under Arm ID number 776924 and classified into “Category B”. Its impact to the device is limited.

##### Description

The VDIV and VSQRT instructions take 14 cycles to execute. When an interrupt is taken a VDIV or VSQRT instruction is not terminated, and completes its execution while the interrupt stacking occurs. If lazy context save of floating point state is enabled then the automatic stacking of the floating point context does not occur until a floating point instruction is executed inside the interrupt service routine.

Lazy context save is enabled by default. When it is enabled, the minimum time for the first instruction in the interrupt service routine to start executing is 12 cycles. In certain timing conditions, and if there is only one or two

instructions inside the interrupt service routine, then the VDIV or VSQRT instruction might not write its result to the register bank or to the FPSCR.

The failure occurs when the following condition is met:

1. The floating point unit is enabled
2. Lazy context saving is not disabled
3. A VDIV or VSQRT is executed
4. The destination register for the VDIV or VSQRT is one of s0 - s15
5. An interrupt occurs and is taken
6. The interrupt service routine being executed does not contain a floating point instruction
7. Within 14 cycles after the VDIV or VSQRT is executed, an interrupt return is executed

A minimum of 12 of these 14 cycles are utilized for the context state stacking, which leaves 2 cycles for instructions inside the interrupt service routine, or 2 wait states applied to the entire stacking sequence (which means that it is not a constant wait state for every access).

In general, this means that if the memory system inserts wait states for stack transactions (that is, external memory is used for stack data), then this erratum cannot be observed.

The effect of this erratum is that the VDIV or VSQRT instruction does not complete correctly and the register bank and FPSCR are not updated, which means that these registers hold incorrect, out of date, data.

### Workaround

A workaround is only required if the floating point unit is enabled. A workaround is not required if the stack is in external memory.

There are two possible workarounds:

- Disable lazy context save of floating point state by clearing LSPEN to 0 (bit 30 of the FPCCR at address 0xE000EF34).
- Disable lazy context save of floating point state by clearing LSPEN to 0 (bit 30 of the FPCCR at address 0xE000EF34).

### 2.1.3 Store immediate overlapping exception return operation might vector to incorrect interrupt

This limitation is registered under Arm ID number 838869 and classified into “Category B (rare)”. Its impact to the device is minor.

#### Description

The core includes a write buffer that permits execution to continue while a store is waiting on the bus. Under specific timing conditions, during an exception return while this buffer is still in use by a store instruction, a late change in selection of the next interrupt to be taken might result in there being a mismatch between the interrupt acknowledged by the interrupt controller and the vector fetched by the processor.

The failure occurs when the following condition is met:

1. The handler for interrupt A is being executed.
2. Interrupt B, of the same or lower priority than interrupt A, is pending.
3. A store with immediate offset instruction is executed to a bufferable location.
  - STR/STRH/STRB <Rt>, [<Rn>,#imm]
  - STR/STRH/STRB <Rt>, [<Rn>,#imm]!
  - STR/STRH/STRB <Rt>, [<Rn>],#imm
4. Any number of additional data-processing instructions can be executed.
5. A BX instruction is executed that causes an exception return.
6. The store data has wait states applied to it such that the data is accepted at least two cycles after the BX is executed.
  - Minimally, this is two cycles if the store and the BX instruction have no additional instructions between them.
  - The number of wait states required to observe this erratum needs to be increased by the number of cycles between the store and the interrupt service routine exit instruction.
7. Before the bus accepts the buffered store data, another interrupt C is asserted which has the same or lower priority as A, but a greater priority than B.

Example:

The processor should execute interrupt handler C, and on completion of handler C should execute the handler for B. If the conditions above are met, then this erratum results in the processor erroneously clearing the pending state of interrupt C, and then executing the handler for B twice. The first time the handler for B is executed it will be at interrupt C's priority level. If interrupt C is pending by a level-based interrupt which is cleared by C's handler then interrupt C will be pending again once the handler for B has completed and the handler for C will be executed.

As the STM32 interrupt C is level based, it eventually becomes pending again and is subsequently handled.

### Workaround

For software not using the memory protection unit, this erratum can be worked around by setting DISDEFWBUF in the Auxiliary Control Register.

In all other cases, the erratum can be avoided by ensuring a DSB occurs between the store and the BX instruction. For exception handlers written in C, this can be achieved by inserting the appropriate set of intrinsics or inline assembly just before the end of the interrupt function, for example:

ARMCC:

```
...
__schedule_barrier();
__asm{DSB};
__schedule_barrier();
}
```

GCC:

```
...
__asm volatile ("dsb 0xf" ::: "memory");
}
```

## 2.2 System

### 2.2.1 Internal voltage reference corrupted upon Stop mode entry with temperature sensing enabled

#### Description

When entering Stop mode with the temperature sensor channel and the associated ADC(s) enabled, the internal voltage reference may be corrupted.

The occurrence of the corruption depends on the supply voltage and the temperature.

The corruption of the internal voltage reference may cause:

- an overvoltage in  $V_{CORE}$  domain
- an overshoot / undershoot of internal clock (LSI, HSI, MSI) frequencies
- a spurious brown-out reset

The limitation applies to Stop 1 and Stop 2 modes.

#### Workaround

Before entering Stop mode:

- Disable the ADC(s) using the temperature sensor signal as input, and/or
- Disable the temperature sensor channel, by clearing the CH17SEL bit of the ADCx\_CCR register.

Disabling both allows consuming less power during Stop mode.

### 2.2.2 Full JTAG configuration without NJTRST pin cannot be used

#### Description

When using the JTAG debug port in Debug mode, the connection with the debugger is lost if the NJTRST pin (PB4) is used as a GPIO. Only the 4-wire JTAG port configuration is impacted.

#### Workaround

Use the SWD debug port instead of the full 4-wire JTAG port.

### 2.2.3 Unstable LSI when it clocks RTC or CSS on LSE

#### Description

The LSI clock can become unstable (duty cycle different from 50 %) and its maximum frequency can become significantly higher than 32 kHz, when:

- LSI clocks the RTC, or it clocks the clock security system (CSS) on LSE (which holds when the LSECSSON bit set), and
- the  $V_{DD}$  power domain is reset while the backup domain is not reset, which happens:
  - upon exiting Shutdown mode
  - if  $V_{BAT}$  is separate from  $V_{DD}$  and  $V_{DD}$  goes off then on
  - if  $V_{BAT}$  is tied to  $V_{DD}$  (internally in the package for products not featuring the VBAT pin, or externally) and a short ( $< 1$  ms)  $V_{DD}$  drop under  $V_{DD}(\min)$  occurs

#### Workaround

Apply one of the following measures:

- Clock the RTC with LSE or HSE/32, without using the CSS on LSE
- If LSI clocks the RTC or when the LSECSSON bit is set, reset the backup domain upon each  $V_{DD}$  power up (when the BORRSTF flag is set). If  $V_{BAT}$  is separate from  $V_{DD}$ , also restore the RTC configuration, backup registers and anti-tampering configuration.

### 2.2.4 LSESYSDIS has no effects if set just before Stop entry

#### Description

The LSE clock disable is only effective two LSE clocks after setting the LSESYSDIS bit of the RCC\_BDCR register. If Stop 2 low-power mode is entered before that instant, the LSE clock is not effectively disabled and its propagation in the device leads to excessive consumption in Stop 2 mode.

#### Workaround

Upon setting the LSESYSDIS bit of the RCC\_BDCR register, wait for at least two LSE clock periods before entering Stop 2 mode.

### 2.2.5 PB8 and PB11 on 48-pin devices with SMPS remain software configurable

#### Description

On 48-pin devices with SMPS support, the non-bonded PB8 and PB11 GPIOs remain software configurable. Their software configuration as floating inputs may lead to increased power consumption.

#### Workaround

Do not configure the PB8 and PB11 GPIOs as floating inputs.

## 2.2.6 First double-word of Flash memory corrupted upon reset or power down while programming

### Description

Power-down and external reset events occurring during Flash memory program operation may result in zeroing its first double-word (64 bits on the address 0x0800 0000). When this occurs, the boot sequence ends immediately after reset, generating Hard Fault.

In most cases, this corruption is temporary and the correct value is read again after a few milliseconds.

*Note:* Corruption of Flash memory word on the address accessed in the instant of a reset event occurring during program or erase operation is a normal (specified) behavior.

### Workaround

Clone the first Flash memory page contents at another Flash memory location to use as a backup page. In the Hard Fault handler:

1. Compare the first Flash memory double-word content with the value backed up. If different:
  - a. Erase the first Flash memory page.
  - b. From the backup page, restore the first Flash memory page contents, excluding the first double-word.
  - c. From the backup page, restore the first Flash memory double-word.
2. Execute a software reset (by setting the SYSRESETREQ bit), to resume execution.

*Note:* In the process of firmware development, the first two 32-bit words of the Flash memory are used by the core as program counter (PC) and as stack pointer (SP), respectively, so this 64-bit value as well as the remaining content of the page can vary upon each build.

## 2.3 FW

### 2.3.1 Code segment unprotected if non-volatile data segment length is zero

#### Description

If during FW configuration the length of firewall-protected non-volatile data segment is set to zero through the LENG[21:8] bitfield of the FW\_NVDSL register, the firewall protection of code segment does not operate.

#### Workaround

Always set the LENG[21:8] bitfield of the FW\_NVDSL register to a non-zero value, even if no firewall protection of data in the non-volatile data segment is required.

## 2.4 QUADSPI

### 2.4.1 First nibble of data not written after dummy phase

#### Description

The first nibble of data to be written to the external Flash memory is lost when the following condition is met:

- QUADSPI is used in indirect write mode.
- At least one dummy cycle is used.

#### Workaround

Use alternate bytes instead of dummy phase to add latency between the address phase and the data phase. This works only if the number of dummy cycles to substitute corresponds to a multiple of eight bits of data.

Example:

- To substitute one dummy cycle, send one alternate byte (only possible in DDR mode with four data lines).
- To substitute two dummy cycles, send one alternate byte in SDR mode with four data lines.
- To substitute four dummy cycles, send two alternate bytes in SDR mode with four data lines, or one alternate byte in SDR mode with two data lines.



- To substitute eight dummy cycles, send one alternate byte in SDR mode with one data line.

## 2.4.2 Wrong data from memory-mapped read after an indirect mode operation

### Description

The first memory-mapped read in indirect mode can yield wrong data if the QUADSPI peripheral enters memory-mapped mode with bits ADDRESS[1:0] of the QUADSPI\_AR register both set.

### Workaround

Before entering memory-mapped mode, apply the following measure, depending on access mode:

- Indirect read mode: clear the QUADSPI\_AR register then issue an abort request to stop reading and to clear the BUSY bit.
- Indirect write mode: clear the QUADSPI\_AR register.

**Caution:** The QUADSPI\_DR register must not be written after clearing the QUADSPI\_AR register.

## 2.5 ADC

### 2.5.1 Writing ADCx\_JSQR when JADCSTART and JQDIS are set might lead to incorrect behavior

#### Description

Writing the ADCx\_JSQR register when there is an on-going injected conversion (JADCSTART = 1) might lead to unpredictable ADC behavior if the queues of context are not enabled (JQDIS = 1).

#### Workaround

None.

### 2.5.2 Wrong ADC result if conversion done late after calibration or previous conversion

#### Description

The result of an ADC conversion done more than 1 ms later than the previous ADC conversion or ADC calibration might be incorrect.

#### Workaround

Perform two consecutive ADC conversions in single, scan or continuous mode. Reject the result of the first conversion and only keep the result of the second.

### 2.5.3 Spurious temperature measurement due to spike noise

#### Description

Depending on the MCU activity, internal interference may cause temperature-dependent spike noise on the temperature sensor output to the ADC, resulting in occasional spurious (outlying) temperature measurement.

#### Workaround

Perform a series of measurements and process the acquired data samples such as to obtain a mean value not affected by the outlying samples.

For this, it is recommended to use interquartile mean (IQM) algorithm with at least 64 samples. IQM is based on rejecting the quarters (quartiles) of sample population with the lowest and highest values and on computing the mean value only using the remaining (interquartile) samples.

The acquired sample values are first sorted from lowest to highest, then the sample sequence is truncated by removing the lowest and highest sample quartiles.

Example:

**Table 4. Measurement result after IQM post-processing**

Data	Sample												Mean
	1	2	3	4	5	6	7	8	9	10	11	12	
Acquired	17.2	10.92	9.56	2.12	9.82	10.72	10.6	3.5	9.46	9.78	9.5	1.1	8.69
Sorted	1.1	2.12	3.5	9.46	9.5	9.56	9.78	9.82	10.6	10.72	10.92	17.2	8.69
Truncated	-	-	-	9.46	9.5	9.56	9.78	9.82	10.6	-	-	-	9.79

The measurement result after the IQM post-processing in the example is 9.79. For consistent results, use a minimum of 64 samples. It is recommended to optimize the code performing the sort task such as to minimize its processing power requirements.

## 2.6 TSC

### 2.6.1 Inhibited acquisition in short transfer phase configuration

#### Description

Some revisions of the reference manual may omit the information that the following configurations of the TSC\_CR register are forbidden:

- The PGPSC[2:0] bitfield set to 000 and the CTPL[3:0] bitfield to 0000 or 0001
- The PGPSC[2:0] bitfield set to 111 and the CTPL[3:0] bitfield to 0000

Failure to respect this restriction leads to an inhibition of the acquisition.

This is a documentation inaccuracy issue rather than a product limitation.

#### Workaround

No application workaround is required.

## 2.7 AES

### 2.7.1 Burst read or write accesses not supported

#### Description

Some revisions of the reference manual may omit the information that the AES peripheral does not support LDM, STM, LDRD and STRD instructions for successive multiple-data (burst) read and write accesses to a contiguous address block.

This is a documentation issue rather than a product limitation.

#### Workaround

No application workaround is required, provided that the multiple-data instructions are not used to access the AES peripheral.

*Note:* To prevent compilers from generating LDM, STM, LDRD and STRD instructions to access the AES peripheral, organize the source code such as to avoid consecutive read or write accesses to neighboring addresses in lower-to-higher order. In case where consecutive read or write accesses to neighboring addresses cannot be avoided, order the source code such as to access higher address first.

### 2.7.2 TAG computation in GCM encryption mode

#### Description

Some revisions of the reference manual may omit the following application guidelines for the device to correctly compute GCM encryption authentication tags when the input data in the last block is inferior to 128 bits.

During GCM encryption payload phase and before inserting a last plaintext block smaller than 128 bits, apply the following steps:

1. Disable the AES peripheral by clearing the EN bit of the AES\_CR register.
2. Change the mode to CTR by writing 010 to the CHMOD[2:0] bitfield of the AES\_CR register.
3. Pad the last block (smaller than 128 bits) with zeros to have a complete block of 128 bits, then write it into AES\_DINR register.
4. Upon encryption completion, read the 128-bit ciphertext from the AES\_DOUTR register and store it as intermediate data.
5. Change again the mode to GCM by writing 011 to the CHMOD[2:0] bitfield of the AES\_CR register.
6. Select Final phase by writing 11 to the GCMPH[1:0] bitfield of the AES\_CR register.
7. In the intermediate data, set to zero the bits corresponding to the padded bits of the last block of payload, then insert the resulting data into AES\_DINR register.
8. Wait for operation completion, and read data on AES\_DOUTR. This data is to be discarded.
9. Apply the normal Final phase as described in the datasheet

This is a documentation issue rather than a product limitation.

#### Workaround

No further application workaround is required, provided that these guidelines are respected.

### 2.7.3 CCM authentication mode not compliant with NIST CMAC

#### Description

Some revisions of the reference manual may omit the information that setting the CHMOD[2:0] bitfield to 100 selects the CCM authentication mode. It is not compliant with NIST CMAC, as defined in Special Publication 800-38B. In order to fully implement the CCM chaining as specified in NIST Special Publication 800-38C, the payload must first be encrypted or decrypted with the AES peripheral set in CTR mode (CHMOD[2:0] = 010), then the message associated data and payload authenticated with the AES peripheral set in CCM mode (CHMOD[2:0] = 100).

This is a documentation issue rather than a product limitation.

#### Workaround

No further application workaround is required, provided that these guidelines are respected.

### 2.7.4 Datatype initial configuration in GCM mode

#### Description

Some revisions of the reference manual may omit the information that GCM generated TAG is not correct if data swapping is not disabled in GCM init phase (GCMPH[1:0] = 00) by setting the DATATYPE[1:0] bitfield of the AES\_CR register to zero.

This is a documentation issue rather than a product limitation.

#### Workaround

No further application workaround is required, provided that these guidelines are respected.

### 2.7.5 Wait until BUSY is low when suspending GCM encryption

#### Description

Some revisions of the reference manual may omit the information that when suspending the GCM encryption of a message, in the payload phase the BUSY flag of the AES\_SR register must be low before saving the AES\_SUSPxR registers in the memory.

This is a documentation issue rather than a product limitation.

### Workaround

No further application workaround is required, provided that these guidelines are respected.

## 2.8 LPTIM

### 2.8.1 MCU may remain stuck in LPTIM interrupt when entering Stop mode

#### Description

This limitation occurs when disabling the low-power timer (LPTIM).

When the user application clears the ENABLE bit in the LPTIM\_CR register within a small time window around one LPTIM interrupt occurrence, then the LPTIM interrupt signal used to wake up the MCU from Stop mode may be frozen in active state. Consequently, when trying to enter Stop mode, this limitation prevents the MCU from entering low-power mode and the firmware remains stuck in the LPTIM interrupt routine.

This limitation applies to all Stop modes and to all instances of the LPTIM. Note that the occurrence of this issue is very low.

#### Workaround

In order to disable a low power timer (LPTIMx) peripheral, do not clear its ENABLE bit in its respective LPTIM\_CR register. Instead, reset the whole LPTIMx peripheral via the RCC controller by setting and resetting its respective LPTIMxRST bit in RCC\_APBxRSTRz register.

## 2.9 RTC and TAMP

### 2.9.1 RTC interrupt can be masked by another RTC interrupt

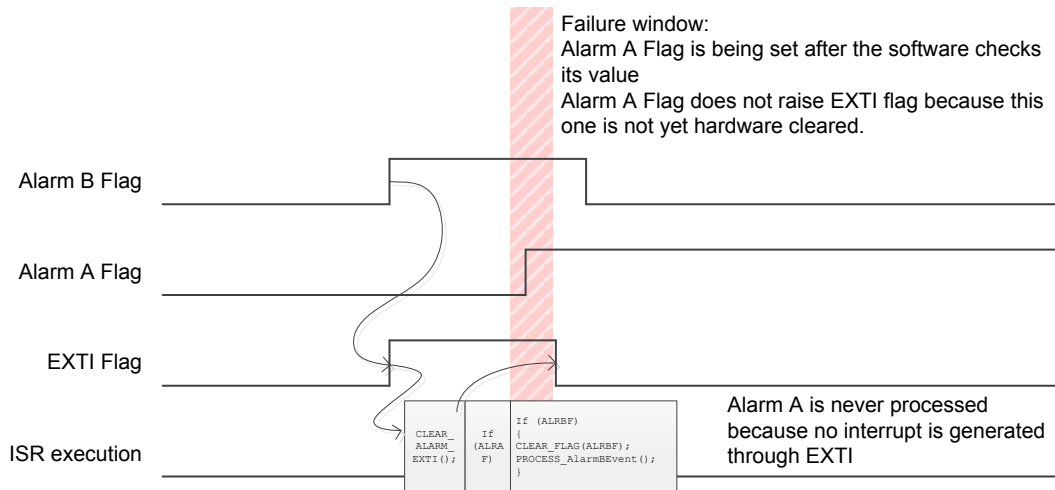
#### Description

One RTC interrupt can mask another RTC interrupt if both share the same EXTI configurable line, such as the RTC Alarm A and Alarm B, of which the event flags are OR-de to the same EXTI line (refer to the **EXTI line connections** table in the **Extended interrupt and event controller (EXTI)** section of the reference manual).

The following code example and figure illustrate the failure mechanism: The Alarm A event is lost (fails to generate interrupt) as it occurs in the failure window, that is, after checking the Alarm A event flag but before the effective clear of the EXTI interrupt flag by hardware. The effective clear of the EXTI interrupt flag is delayed with respect to the software instruction to clear it.

Alarm interrupt service routine:

```
void RTC_Alarm_IRQHandler(void)
{
    CLEAR_ALARM_EXTI(); /* Clear the EXTI line flag for RTC alarms*/
    If(ALRAF) /* Check if Alarm A triggered ISR */
    {
        CLEAR_FLAG(ALRAF); /* Clear the Alarm A interrupt pending bit */
        PROCESS_AlarmAEvent(); /* Process Alarm A event */
    }
    If(ALRBF) /* Check if Alarm B triggered ISR */
    {
        CLEAR_FLAG(ALRBF); /* Clear the Alarm B interrupt pending bit */
        PROCESS_AlarmBEvent(); /* Process Alarm B event */
    }
}
```

**Figure 1. Masked RTC interrupt**

**Workaround**

In the interrupt service routine, apply three consecutive event flag checks - source one, source two, and source one again, as in the following code example:

```
void RTC_Alarm_IRQHandler(void)
{
    CLEAR_ALARM_EXTI(); /* Clear the EXTI's line Flag for RTC Alarm */
    If(ALRAF) /* Check if AlarmA triggered ISR */
    {
        CLEAR_FLAG(ALRAF); /* Clear the AlarmA interrupt pending bit */
        PROCESS_AlarmAEvent(); /* Process AlarmA Event */
    }
    If(ALRBF) /* Check if AlarmB triggered ISR */
    {
        CLEAR_FLAG(ALRBF); /* Clear the AlarmB interrupt pending bit */
        PROCESS_AlarmBEvent(); /* Process AlarmB Event */
    }
    If(ALRAF) /* Check if AlarmA triggered ISR */
    {
        CLEAR_FLAG(ALRAF); /* Clear the AlarmA interrupt pending bit */
        PROCESS_AlarmAEvent(); /* Process AlarmA Event */
    }
}
```

**2.9.2 Calendar initialization may fail in case of consecutive INIT mode entry**
**Description**

If the INIT bit of the RTC\_ISR register is set between one and two RTCCLK cycles after being cleared, the INITF flag is set immediately instead of waiting for synchronization delay (which should be between one and two RTCCLK cycles), and the initialization of registers may fail.

Depending on the INIT bit clearing and setting instants versus the RTCCLK edges, it can happen that, after being immediately set, the INITF flag is cleared during one RTCCLK period then set again. As writes to calendar registers are ignored when INITF is low, a write during this critical period might result in the corruption of one or more calendar registers.

**Workaround**

After exiting the initialization mode, clear the BYPSHAD bit (if set) then wait for RSF to rise, before entering the initialization mode again.

**Note:** *It is recommended to write all registers in a single initialization session to avoid accumulating synchronization delays.*

### 2.9.3 Spurious RTC alarm EXTI line event following RTC WUT interrupt

#### Description

As expected, WUT interrupt (if enabled in the RTC) generates an event on the EXTI line 20 of the event controller. However, it also causes a spurious event on the EXTI line 18 that should only respond to alarm interrupts and not to WUT interrupts.

#### Workaround

Upon EXTI 18 event, identify the source of interrupt by reading WUT and alarm interrupt flags.

### 2.9.4 RTC\_REFIN and RTC\_OUT on PB2 not operating in Stop 2 mode

#### Description

In Stop 2 low-power mode, the RTC\_REFIN function does not operate and the RTC\_OUT function does not operate if mapped on the PB2 pin.

#### Workaround

Apply one of the following measures:

- Use Stop 1 mode instead of Stop 2. This ensures the operation of both functions.
- Map RTC\_OUT to the PC13 pin. This ensures the operation of the RTC\_OUT function in either low-power mode. However, it has no effect to the RTC\_REFIN function.

## 2.10 I2C

### 2.10.1 10-bit master mode: new transfer cannot be launched if first part of the address is not acknowledged by the slave

#### Description

An I<sup>2</sup>C-bus master generates STOP condition upon non-acknowledge of I<sup>2</sup>C address that it sends. This applies to 7-bit address as well as to each byte of 10-bit address.

When the MCU set as I<sup>2</sup>C-bus master transmits a 10-bit address of which the first byte (5-bit header + 2 MSBs of the address + direction bit) is not acknowledged, the MCU duly generates STOP condition but it then cannot start any new I<sup>2</sup>C-bus transfer. In this spurious state, the NACKF flag of the I2C\_ISR register and the START bit of the I2C\_CR2 register are both set, while the START bit should normally be cleared.

#### Workaround

In 10-bit-address master mode, if both NACKF flag and START bit get simultaneously set, proceed as follows:

1. Wait for the STOP condition detection (STOPF = 1 in I2C\_ISR register).
2. Disable the I2C peripheral.
3. Wait for a minimum of three APB cycles.
4. Enable the I2C peripheral again.

### 2.10.2 Wrong behavior in Stop mode when wakeup from Stop mode is disabled in I2C

#### Description

If the wakeup from Stop mode by I2C is disabled (WUPEN = 0), the correct use of the I2C peripheral is to disable it (PE = 0) before entering Stop mode, and re-enable it when back in Run mode.

Some reference manual revisions may omit this information.

Failure to respect the above while the MCU operating as slave or as master in multi-master topology enters Stop mode during a transfer ongoing on the I<sup>2</sup>C-bus may lead to the following:

1. BUSY flag is wrongly set when the MCU exits Stop mode. This prevents from initiating a transfer in master mode, as the START condition cannot be sent when BUSY is set.
2. If clock stretching is enabled (NOSTRETCH = 0), the SCL line is pulled low by I2C and the transfer stalled as long as the MCU remains in Stop mode.  
The occurrence of such condition depends on the timing configuration, peripheral clock frequency, and I<sup>2</sup>C-bus frequency.

This is a description inaccuracy issue rather than a product limitation.

#### Workaround

No application workaround is required.

### 2.10.3 Wrong data sampling when data setup time ( $t_{\text{SU;DAT}}$ ) is shorter than one I2C kernel clock period

#### Description

The I<sup>2</sup>C-bus specification and user manual specify a minimum data setup time ( $t_{\text{SU;DAT}}$ ) as:

- 250 ns in Standard mode
- 100 ns in Fast mode
- 50 ns in Fast mode Plus

The MCU does not correctly sample the I<sup>2</sup>C-bus SDA line when  $t_{\text{I2C}}$  kernel clock (I<sup>2</sup>C-bus peripheral clock) period: the previous SDA value is sampled instead of the current one. This can result in a wrong receipt of slave address, data byte, or acknowledge bit.

#### Workaround

Increase the I2C kernel clock frequency to get I2C kernel clock period within the transmitter minimum data setup time. Alternatively, increase transmitter's minimum data setup time. If the transmitter setup time minimum value corresponds to the minimum value provided in the I<sup>2</sup>C-bus standard, the minimum I2CCLK frequencies are as follows:

- In Standard mode, if the transmitter minimum setup time is 250 ns, the I2CCLK frequency must be at least 4 MHz.
- In Fast mode, if the transmitter minimum setup time is 100 ns, the I2CCLK frequency must be at least 10 MHz.
- In Fast-mode Plus, if the transmitter minimum setup time is 50 ns, the I2CCLK frequency must be at least 20 MHz.

### 2.10.4 Spurious bus error detection in master mode

#### Description

In master mode, a bus error can be detected spuriously, with the consequence of setting the BERR flag of the I2C\_SR register and generating bus error interrupt if such interrupt is enabled. Detection of bus error has no effect on the I<sup>2</sup>C-bus transfer in master mode and any such transfer continues normally.

#### Workaround

If a bus error interrupt is generated in master mode, the BERR flag must be cleared by software. No other action is required and the ongoing transfer can be handled normally.

### 2.10.5 Last-received byte loss in reload mode

#### Description

If in master receiver mode or slave receive mode with SBC = 1 the following conditions are all met:

- I<sup>2</sup>C-bus stretching is enabled (NOSTRETCH = 0)
- RELOAD bit of the I2C\_CR2 register is set
- NBYTES bitfield of the I2C\_CR2 register is set to N greater than 1

- byte N is received on the I<sup>2</sup>C-bus, raising the TCR flag
- N - 1 byte is not yet read out from the data register at the instant TCR is raised,

then the SCL line is pulled low (I<sup>2</sup>C-bus clock stretching) and the transfer of the byte N from the shift register to the data register inhibited until the byte N-1 is read and NBYTES bitfield reloaded with a new value, the latter of which also clears the TCR flag. As a consequence, the software cannot get the byte N and use its content before setting the new value into the NBYTES field.

#### Workaround

- In master mode or in slave mode with SBC = 1, use the reload mode with NBYTES = 1.
- In master receiver mode, if the number of bytes to transfer is greater than 255, do not use the reload mode. Instead, split the transfer into sections not exceeding 255 bytes and separate them with repeated START conditions.
- Make sure, for example through the use of DMA, that the byte N - 1 is always read before the TCR flag is raised.

The last workaround in the list must be evaluated carefully for each application as the timing depends on factors such as the bus speed, interrupt management, software processing latencies, and DMA channel priority.

### 2.10.6 Spurious master transfer upon own slave address match

#### Description

When the device is configured to operate at the same time as master and slave (in a multi-master I<sup>2</sup>C-bus application), a spurious master transfer may occur under the following condition:

- Another master on the bus is in process of sending the slave address of the device (the bus is busy).
- The device initiates a master transfer by bit set before the slave address match event (the ADDR flag set in the I2C\_ISR register) occurs.
- After the ADDR flag is set:
  - the device does not write I2C\_CR2 before clearing the ADDR flag, or
  - the device writes I2C\_CR2 earlier than three I2C kernel clock cycles before clearing the ADDR flag

In these circumstances, even though the START bit is automatically cleared by the circuitry handling the ADDR flag, the device spuriously proceeds to the master transfer as soon as the bus becomes free. The transfer configuration depends on the content of the I2C\_CR2 register when the master transfer starts. Moreover, if the I2C\_CR2 is written less than three kernel clocks before the ADDR flag is cleared, the I2C peripheral may fall into an unpredictable state.

#### Workaround

Upon the address match event (ADDR flag set), apply the following sequence.

Normal mode (SBC = 0):

1. Set the ADDRCONF bit.
2. Before Stop condition occurs on the bus, write I2C\_CR2 with the START bit low.

Slave byte control mode (SBC = 1):

1. Write I2C\_CR2 with the slave transfer configuration and the START bit low.
2. Wait for longer than three I2C kernel clock cycles.
3. Set the ADDRCONF bit.
4. Before Stop condition occurs on the bus, write I2C\_CR2 again with its current value.

The time for the software application to write the I2C\_CR2 register before the Stop condition is limited, as the clock stretching (if enabled), is aborted when clearing the ADDR flag.

Polling the BUSY flag before requesting the master transfer is not a reliable workaround as the bus may become busy between the BUSY flag check and the write into the I2C\_CR2 register with the START bit set.

## 2.11 USART



### 2.11.1 RTS is active while RE = 0 or UE = 0

#### Description

The RTS line is driven low as soon as RTSE bit is set, even if the USART is disabled (UE = 0) or the receiver is disabled (RE = 0), that is, not ready to receive data.

#### Workaround

Upon setting the UE and RE bits, configure the I/O used for RTS into alternate function.

## 2.12 SPI

### 2.12.1 BSY bit may stay high at the end of data transfer in slave mode

#### Description

BSY flag may sporadically remain high at the end of a data transfer in slave mode. This occurs upon coincidence of internal CPU clock and external SCK clock provided by master.

In such an event, if the software only relies on BSY flag to detect the end of SPI slave data transaction (for example to enter low-power mode or to change data line direction in half-duplex bidirectional mode), the detection fails.

As a conclusion, the BSY flag is unreliable for detecting the end of data transactions.

#### Workaround

Depending on SPI operating mode, use the following means for detecting the end of transaction:

- When NSS hardware management is applied and NSS signal is provided by master, use NSS flag.
- In SPI receiving mode, use the corresponding RXNE event flag.
- In SPI transmit-only mode, use the BSY flag in conjunction with a timeout expiry event. Set the timeout such as to exceed the expected duration of the last data frame and start it upon TXE event that occurs with the second bit of the last data frame. The end of the transaction corresponds to either the BSY flag becoming low or the timeout expiry, whichever happens first.

Prefer one of the first two measures to the third as they are simpler and less constraining.

Alternatively, apply the following sequence to ensure reliable operation of the BSY flag in SPI transmit mode:

1. Write last data to data register.
2. Poll the TXE flag until it becomes high, which occurs with the second bit of the data frame transfer.
3. Disable SPI by clearing the SPE bit mandatorily before the end of the frame transfer.
4. Poll the BSY bit until it becomes low, which signals the end of transfer.

*Note:* The alternative method can only be used with relatively fast CPU speeds versus relatively slow SPI clocks or/and long last data frames. The faster is the software execution, the shorter can be the duration of the last data frame.

### 2.12.2 Wrong CRC in full-duplex mode handled by DMA with imbalanced setting of data counters

#### Description

When SPI is handled by DMA in full-duplex master or slave mode with CRC enabled, the CRC computation may temporarily freeze for the ongoing frame, which results in corrupted CRC.

This happens when the receive counter reaches zero upon the receipt of the CRC pattern (as the receive counter was set to a value greater, by CRC length, than the transmit counter). An internal signal dedicated to receive-only mode is left unduly pending. Consequently, the signal can cause the CRC computation to freeze during a next transaction in which DMA TXE event service is accidentally delayed (for example, due to DMA servicing a request from another channel).

#### Workaround

Apply one of the following measures prior to each full-duplex SPI transaction:

- Set the DMA transmission and reception data counters to equal values. Upon the transaction completion, read the CRC pattern out from RxFIFO separately by software.
- Reset the SPI peripheral via peripheral reset register.

### 2.12.3 CRC error in SPI slave mode if internal NSS changes before CRC transfer

#### Description

Some reference manual revisions may omit the information that the device operating as SPI slave must be configured in software NSS control if the SPI master pulses the NSS (for example in NSS pulse mode). Otherwise, the transition of the internal NSS signal after the CRCNEXT flag is set might result in wrong CRC value computed by the device and, as a consequence, in a CRC error. As a consequence, the NSS pulse mode cannot be used along with the CRC function.

This is a documentation error rather than a product limitation.

#### Workaround

No application workaround is required as long as the device operating as SPI slave is duly configured in software NSS control.

## Revision history

**Table 5. Document revision history**

Date	Version	Changes
15-Oct-2018	1	Initial release.

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